FRIDAY AM

XRD

STRESS ANALYSIS — EVERGREEN B

Chairs: **C. Goldsmith**, IBM, Hopewell Junction, NY
T. Watkins, Oak Ridge National Laboratory, Oak Ridge, TN

8:30 D-50 *Invited*—Thermo-Mechanical Behavior of Thin Films and Small Structures Characterized by Synchrotron X-ray Diffraction
J. Keckes, *University Leoben and Austrian Academy of Sciences, Leoben, Austria*

9:00 D-48 XRD Stress Analyses on Surfaces with Curvature Radius below 1mm, a New Challenge!
A. Haase, M. Klatt, A. Schafmeister, R. Stabenow, *GE Sensing & Inspection Technologies GmbH, Ahrensburg, Germany*

9:20 D-101 *Invited*—A Next Generation Neutron Diffraction Strain Scanner for Steady-State Sources
R.B. Rogge, *Canadian Neutron Beam Centre, National Research Council, Canada*

9:50 Break

10:10 D-16 *Invited*—Commissioning Results and New Scientific Opportunities at Vulcan—The SNS Materials Science and Engineering Diffractometor
K. An, X.-L. Wang, A.D. Stoica, H. Skorpenske, D. Ma, C.R. Hubbard, *Oak Ridge National Laboratory, Oak Ridge, TN*
T.M. Holden, *Northern Stress Technology, Deep River, Canada*
P.K. Liaw, H. Choo, *University of Tennessee, Knoxville, TN*

10:40 D-96 In-Situ Neutron Diffraction Study of Residual Stress in Steel Ammonia Nurse Tank Welds
T.A. Sisneros, D.W. Brown, *Los Alamos National Laboratory, Los Alamos, NM*
A. Russel, *Ames National Laboratory, Ames, IA*
S. Chumbley, A. Becker, *Iowa State University, Ames, IA*

FRIDAY AM

XRF

TRACE ANALYSIS — EVERGREEN C

Chair: **P. Wobrauschek**, Atominstitut, Vienna University of Technology, Vienna, Austria

8:30 F-72 *Invited*—TXRF- A Versatile Tool for Trace Element Analysis: A Review
P. Wobrauschek, *Atominstitut, Vienna Univ. of Technology, Vienna, Austria*

9:00 F-31 Discovering the Selenium Metabolism and Its Impact for Health Prevention by TXRF
A. Gross, H. Stosnach, *Bruker Nano GmbH, Berlin, Germany*
K. Renko, T. Behrends, L. Schomburg, *Charité Berlin, Berlin, Germany*

9:20 F-76 *Invited*—Different Applications of Polycapillaries to X-ray Spectroscopy
H.J. Sánchez, R.D. Pérez, *Universidad Nacional de Córdoba, Argentina*
C.A. Pérez, *Laboratório Nacional de Luz Síncrotron, Campinas, Brasil*

9:50 F-33 Trace Element Detection Using Monochromatic Wavelength Dispersive X-ray Fluorescence
G.J. Havrilla, M. Collins, V. Montoya, *Los Alamos National Laboratory, Los Alamos, NM*
Z. Chen, F. Wei, *X-ray Optical Systems, East Greenbush, NY*

10:10 Break

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